

Maximum Ratings (@ $T_A = +25^{\circ}C$, unless otherwise specified.)

Characteristic			Symbol	Value	Unit
Drain-Source Voltage			VDSS	40	V
Gate-Source Voltage			V _{GSS}	±20	V
Continuous Drain Current (Note 6) Vgs = 10V	Steady State	T _A = +25°C T _A = +70°C	lD	4.6 3.7	А
Maximum Body Diode Forward Current (Note 6)			Is	1.5	Α
Pulsed Drain Current (10µs Pulse, Duty Cycle = 1%)			I _{DM}	25	Α
Pulsed Source Current (10µs Pulse, Duty Cycle = 1%)			lsм	25	Α

Thermal Characteristics

Characteristic		Symbol	Value	Unit
Power Dissipation (Note 5)		PD	0.72	W
Thermal Resistance, Junction to Ambient (Note 5)	Steady State	Reja	171	°C/W
Power Dissipation (Note 6)		PD	1.4	W
Thermal Resistance, Junction to Ambient (Note 6)	Steady State	Reja	93	°C/W
Operating and Storage Temperature Range		T _{J,} T _{STG}	-55 to +150	°C

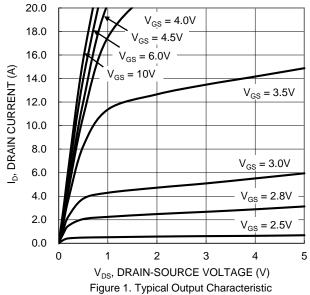
Electrical Characteristics (@T_A = +25°C, unless otherwise specified.)

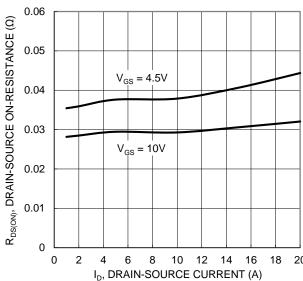
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 7)							
Drain-Source Breakdown Voltage	BV _{DSS}	40	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$	
Zero Gate Voltage Drain Current	IDSS	_	_	1	μΑ	V _{DS} = 40V, V _{GS} = 0V	
Gate-Source Leakage	Igss	_	_	±100	nA	$V_{GS} = \pm 20V$, $V_{DS} = 0V$	
ON CHARACTERISTICS (Note 7)					•		
Gate Threshold Voltage	V _{GS(TH)}	1	_	3	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$	
Static Drain-Source On-Resistance	RDS(ON)	_	30	42	mΩ	V _G S = 10V, I _D = 4.3A	
Static Drain-Source On-Resistance		_	40	52		V _{GS} = 4.5V, I _D = 3.9A	
Diode Forward Voltage	V_{SD}	_	0.7	1.1	V	V _{GS} = 0V, I _S = 1.25A	
DYNAMIC CHARACTERISTICS (Note 8)							
Input Capacitance	Ciss	_	574	_		V _{DS} = 20V, V _{GS} = 0V, f = 1MHz	
Output Capacitance	Coss	_	87.8	_	pF		
Reverse Transfer Capacitance	Crss	_	38.7	_			
Gate Resistance	Rg	_	1.6	_	Ω	$V_{DS} = 0V$, $V_{GS} = 0V$, $f = 1MHz$	
Total Gate Charge (V _{GS} = 4.5V)	Qg	_	5.9	_			
Total Gate Charge (V _{GS} = 10V)	Qg	_	12.5	_	nC	$V_{DS} = 20V, I_{D} = 3.9A$	
Gate-Source Charge	Qgs	_	1.7	_	nc nc		
Gate-Drain Charge	Qgd	_	2.2	_			
Turn-On Delay Time	td(on)	_	3.1	_		$V_{DD} = 20V, V_{GS} = 10V,$ $R_L = 20\Omega, R_G = 6\Omega$	
Turn-On Rise Time	t _R	_	2.6	_			
Turn-Off Delay Time	t _{D(OFF)}	_	15	_	ns		
Turn-Off Fall Time	tF	_	5.5	_		1	
Reverse Recovery Time	trr	_	6.5	_	ns		
Reverse Recovery Charge	Q _{RR}	_	1.2	_	nC	-I _F = 3.9A, di/dt = 500A/μs	

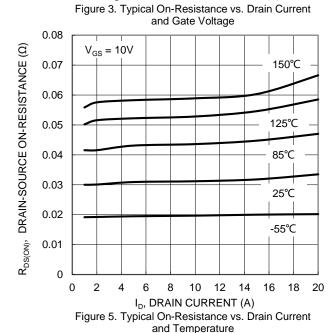
Notes:

Device mounted on FR-4 substrate PC board, 2oz copper, with minimum recommended pad layout.
Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1inch square copper plate.
Short duration pulse test used to minimize self-heating effect.
Guaranteed by design. Not subject to product testing.









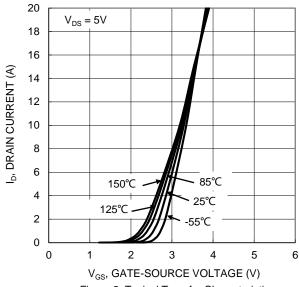
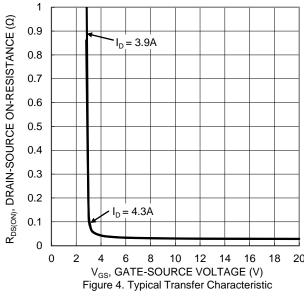


Figure 2. Typical Transfer Characteristic



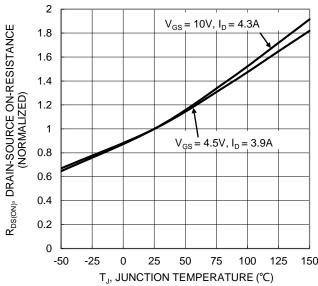
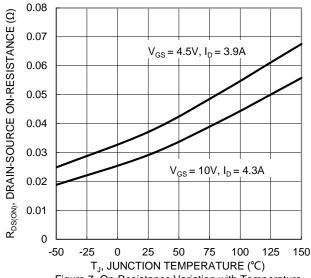
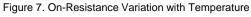
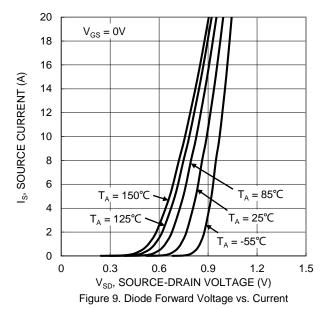


Figure 6. On-Resistance Variation with Temperature









10 9 8 7 6 5 4 3 $V_{DS} = 20V, I_{D} = 3.9A$ 2 1 0 0 2 6 8 10 12 Q_a (nC) Figure 11. Gate Charge

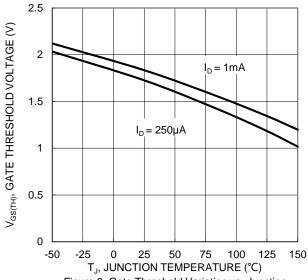


Figure 8. Gate Threshold Variation vs. Junction Temperature

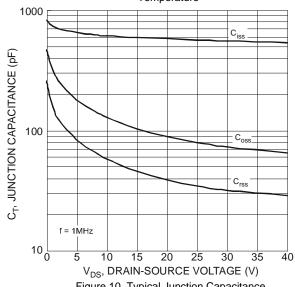
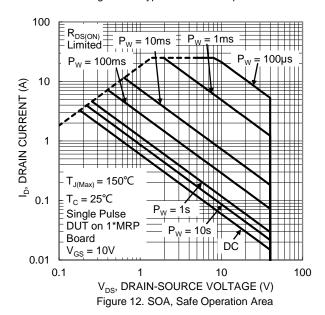


Figure 10. Typical Junction Capacitance





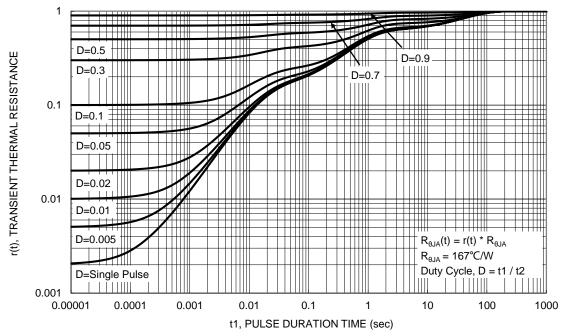


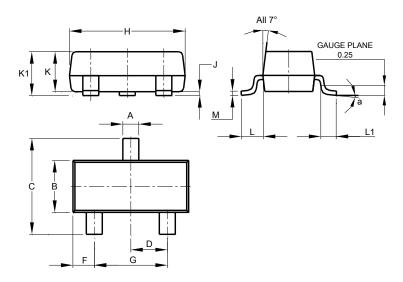
Figure 13. Transient Thermal Resistance



Package Outline Dimensions

Please see http://www.diodes.com/package-outlines.html for the latest version.

SOT23

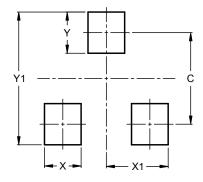


SOT23					
Dim	Min Max Ty		Тур		
Α	0.37	0.51	0.40		
В	1.20	1.40	1.30		
С	2.30	2.50	2.40		
D	0.89	1.03	0.915		
F	0.45	0.60	0.535		
G	1.78	2.05	1.83		
Н	2.80	3.00	2.90		
J	0.013	0.10	0.05		
K	0.890	1.00	0.975		
K1	0.903	1.10	1.025		
L	0.45	0.61	0.55		
L1	0.25	0.55	0.40		
М	0.085	0.150	0.110		
а	0°	8°			
All Dimensions in mm					

Suggested Pad Layout

Please see http://www.diodes.com/package-outlines.html for the latest version.

SOT23



Dimensions	Value (in mm)
C	2.0
Х	0.8
X1	1.35
Y	0.9
Y1	2.9



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